
Low Voltage Bandgap References and High PSRR Mechanism

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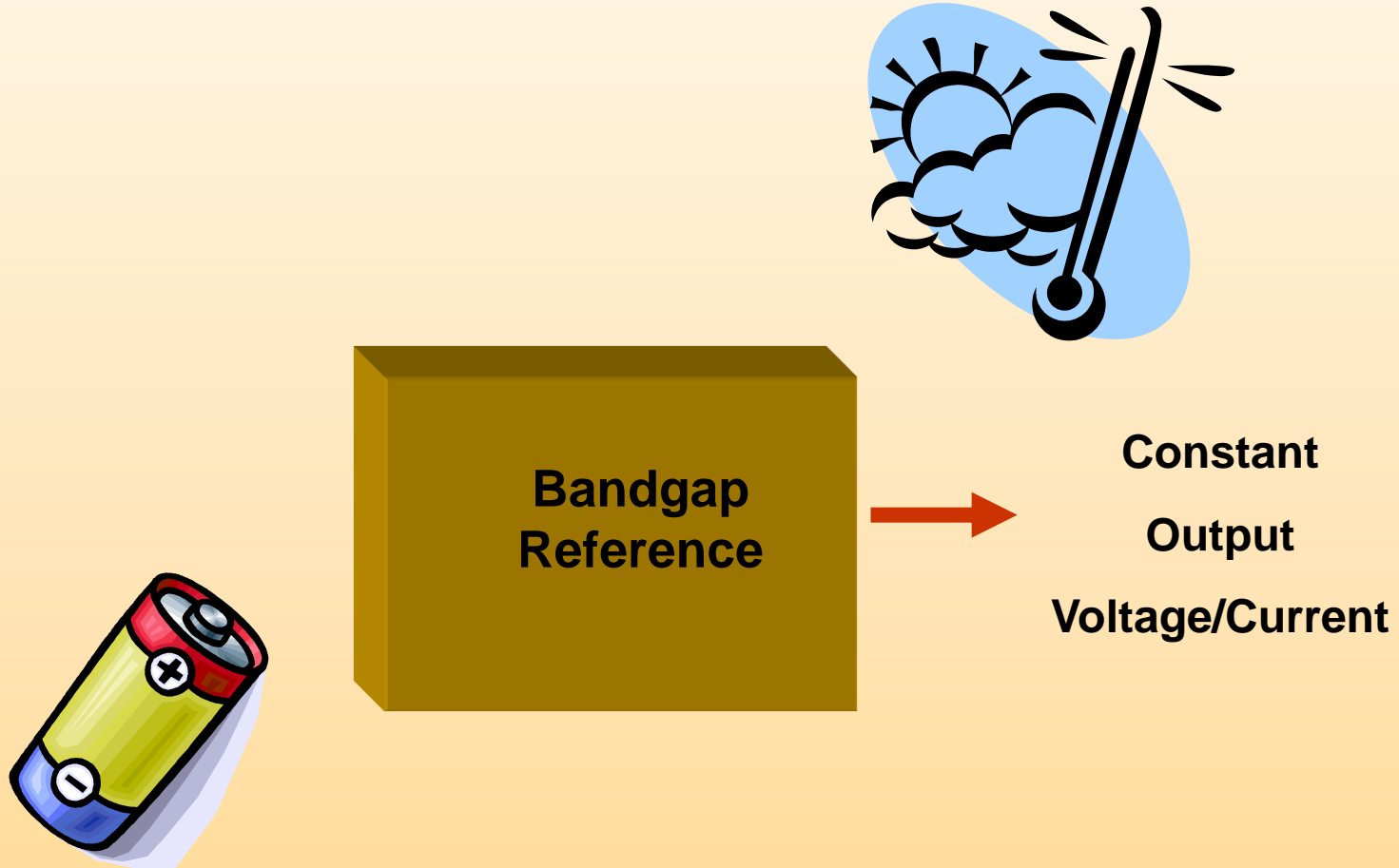
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Outline

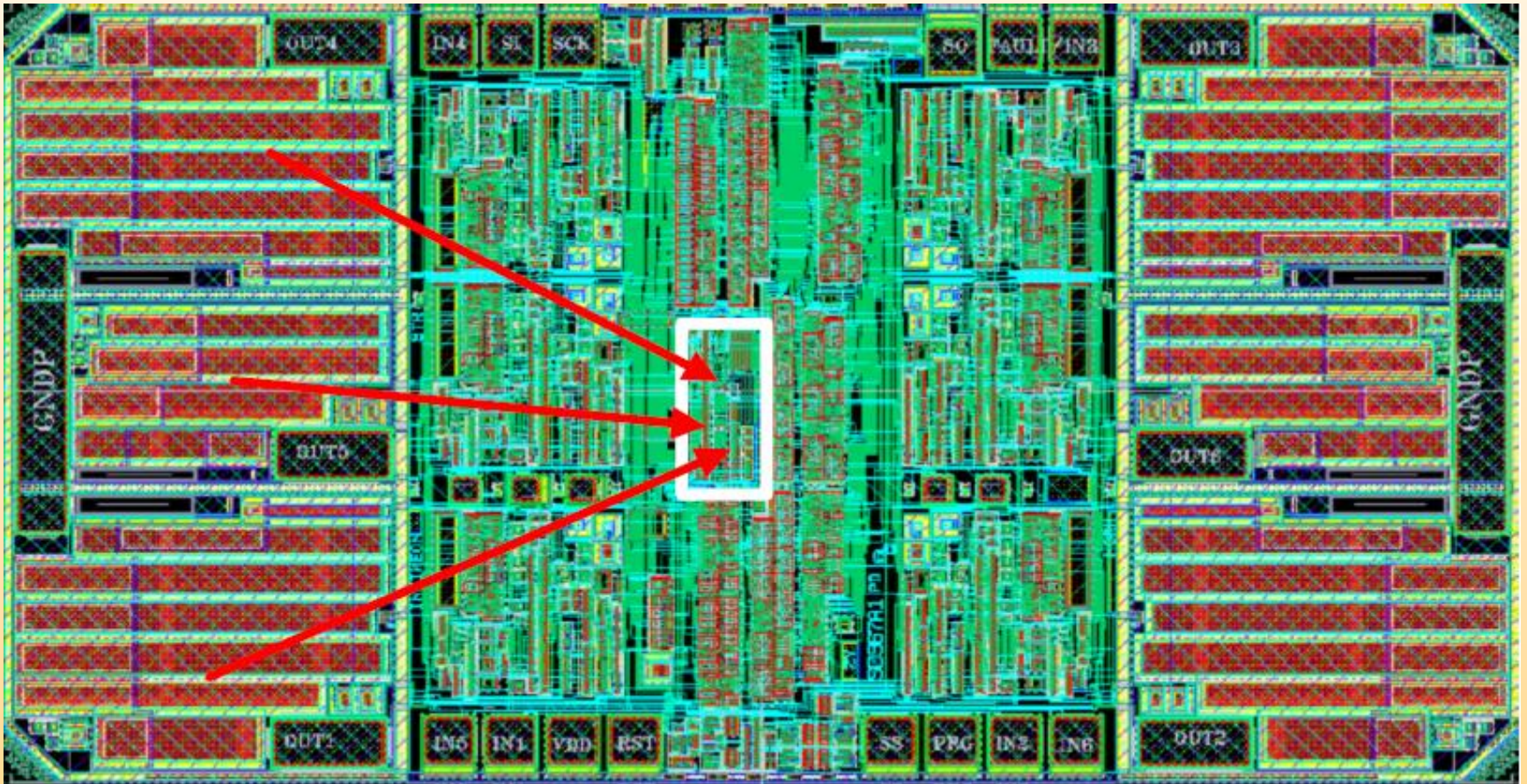
- **The Necessity of Bandgap Reference**
- **Zener Diode References**
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The Necessity of Bandgap Reference



BGR is an important part of analog and mixed signal integrated circuits



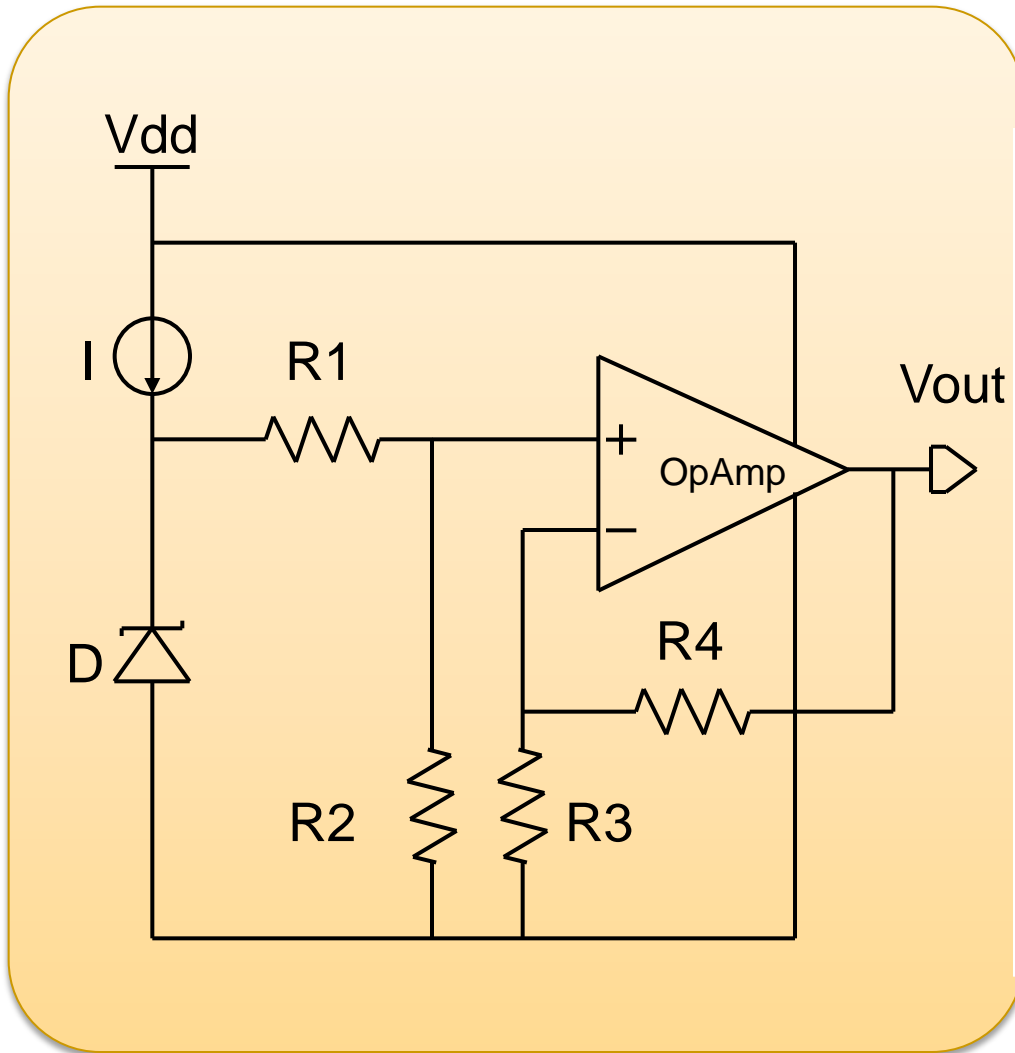
Requirements

- Supply and Process-independent biasing
- Well defined behavior with temperature
PVT independence

- Output noise
- Output impedance
- Power dissipation

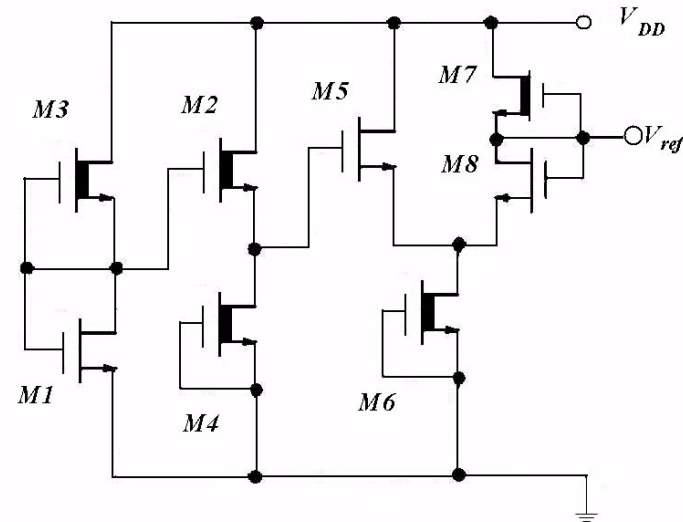
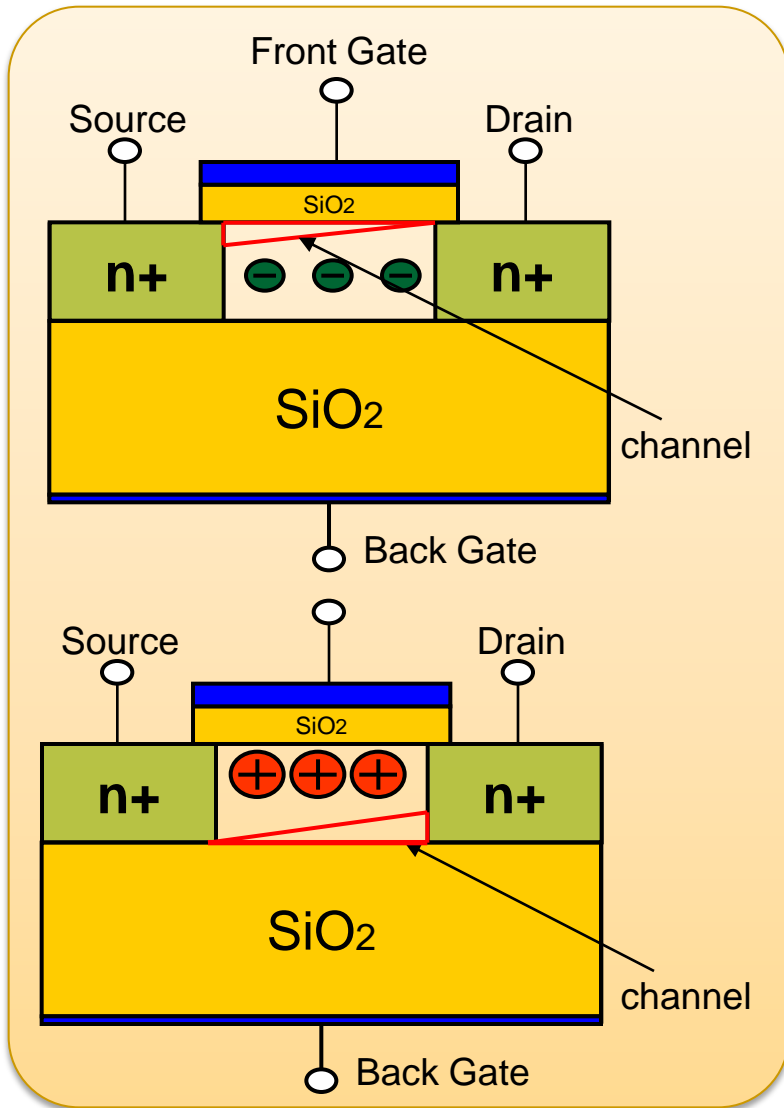


Zener Diode References



- **Buried zener diode method**
- **Buried transistor base emitter method**

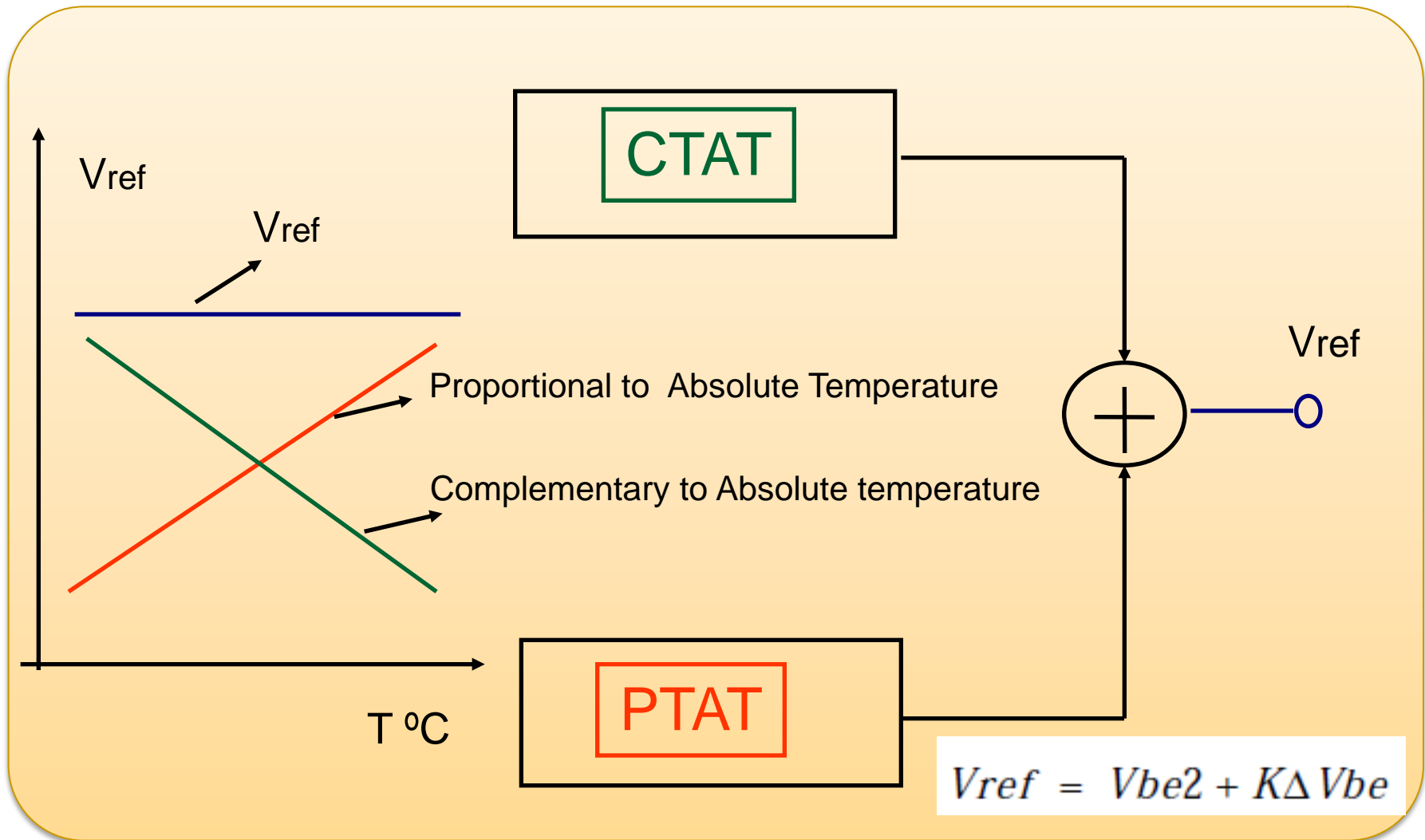
Enhancement and Depletion Reference



$$V_{ref} = V_{GSE} - V_{GSD} = V_{TE} + \sqrt{\frac{I_D}{K_E}} - V_{TD} - \sqrt{\frac{I_D}{K_D}}$$

$$I_D = f(T), K_E = \mu_E C_{ox} \frac{W}{L} = \mu_E(T) C_{ox} \frac{W}{L}$$

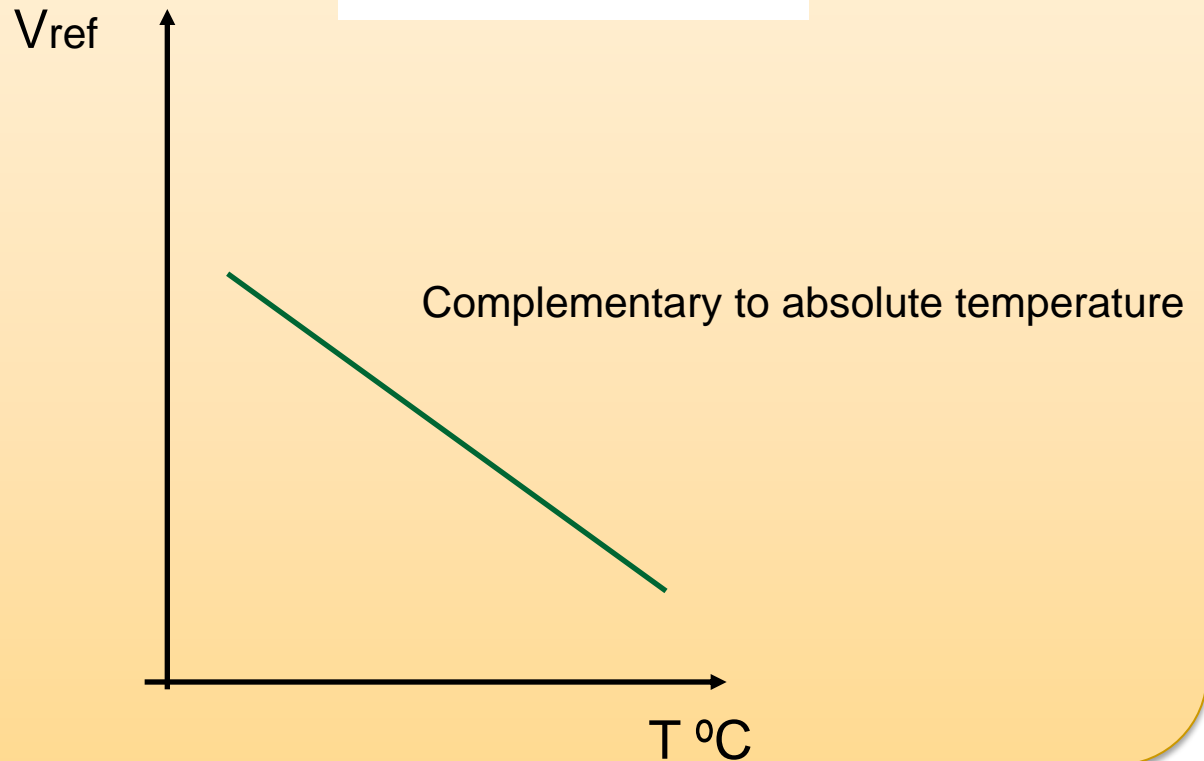
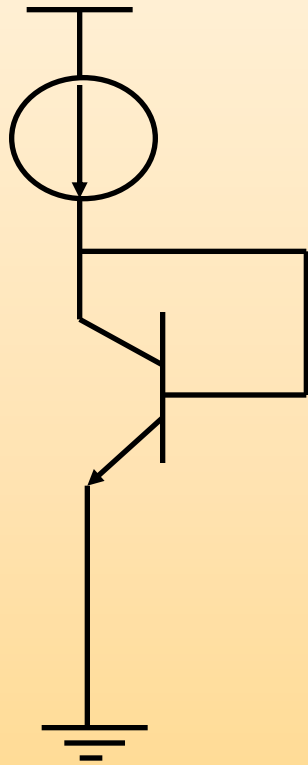
Bandgap Reference Approach



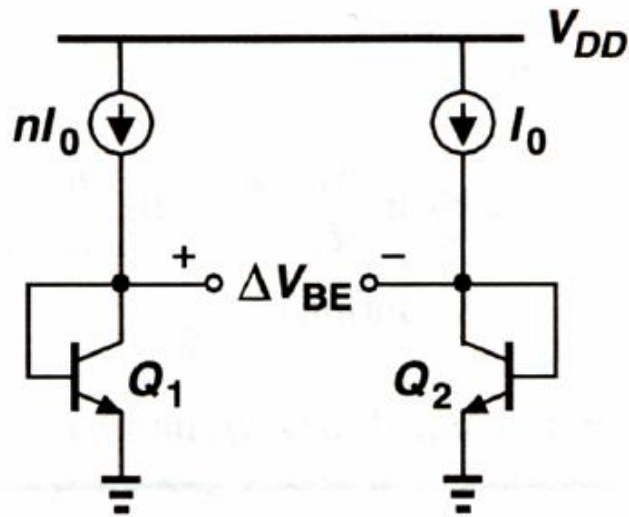
Complimentar to Absolute Temperature CTAT

Forward-biased base-emitter junction of a bipolar transistor has an I-V relationship given by

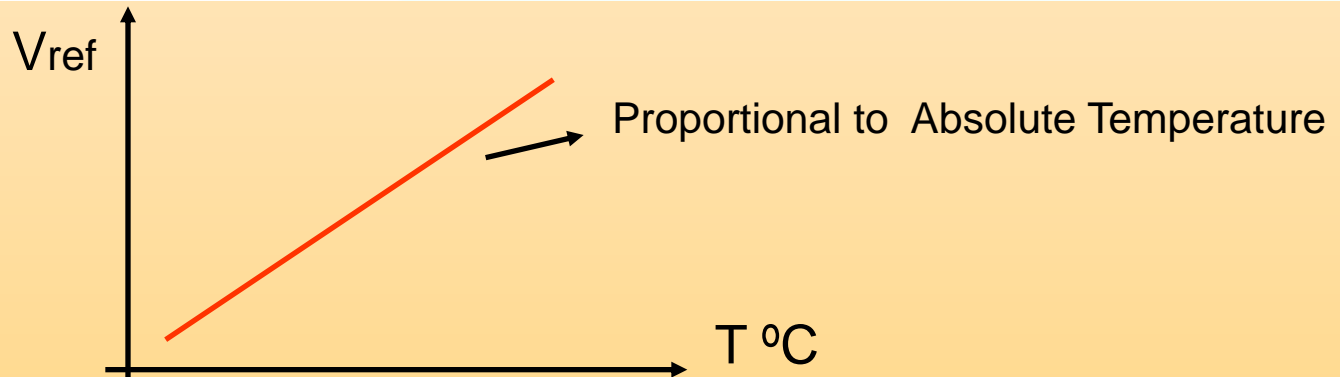
$$I_c = I_s e^{qV_{BE} / kT}$$



Proportional to Absolute Temperature PTAT



$$\begin{aligned}\Delta V_{BE} &= V_{BE1} - V_{BE2} \\ &= V_T \ln \frac{nI_0}{I_{S1}} - V_T \ln \frac{I_0}{I_{S2}} \\ &= V_T \ln n. \text{ PTAT voltage}\end{aligned}$$



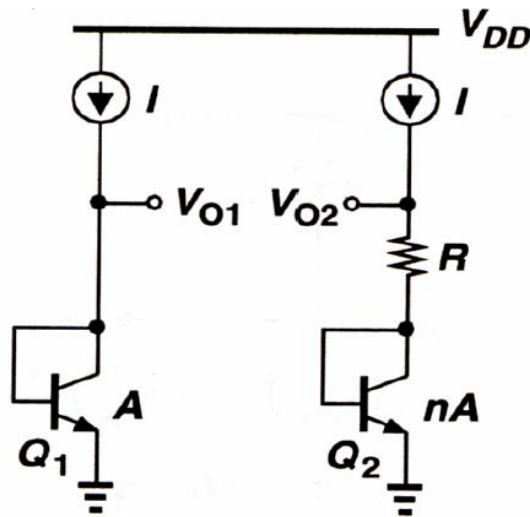
CMOS Bandgap Reference

Bandgap reference : $V_{ref} = V_{BE} + K V_T$

$$\partial V_{BE} / \partial T \approx -1.5 \text{ mV}/^\circ\text{K}$$

$$\partial V_T / \partial T \approx +0.087 \text{ mV}/^\circ\text{K}$$

$$V_{REF} \approx V_{BE} + 17.2 V_T$$

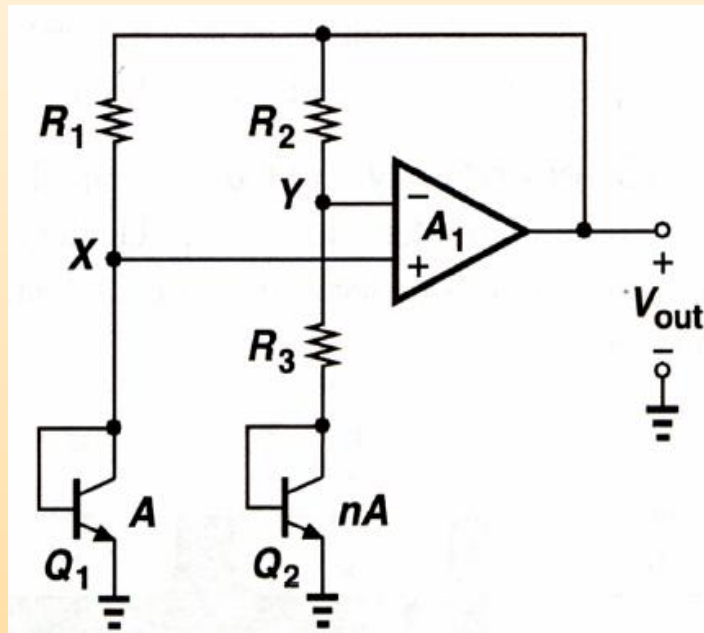


$$V_{BE1} = RI + V_{BE2}$$

$$RI = V_{BE1} - V_{BE2} = V_T \ln n$$

$$\begin{aligned} V_{o2} &= RI + V_{BE2} \\ &= V_T \cdot \ln n + V_{BE2} \end{aligned}$$

CMOS Bandgap Reference Circuit



$$\begin{aligned} V_{out} &= V_{BE2} + \frac{V_T \ln n}{R_3} (R_3 + R_2) \\ &= V_{BE2} + (V_T \ln n) \left(1 + \frac{R_2}{R_3} \right) \end{aligned}$$

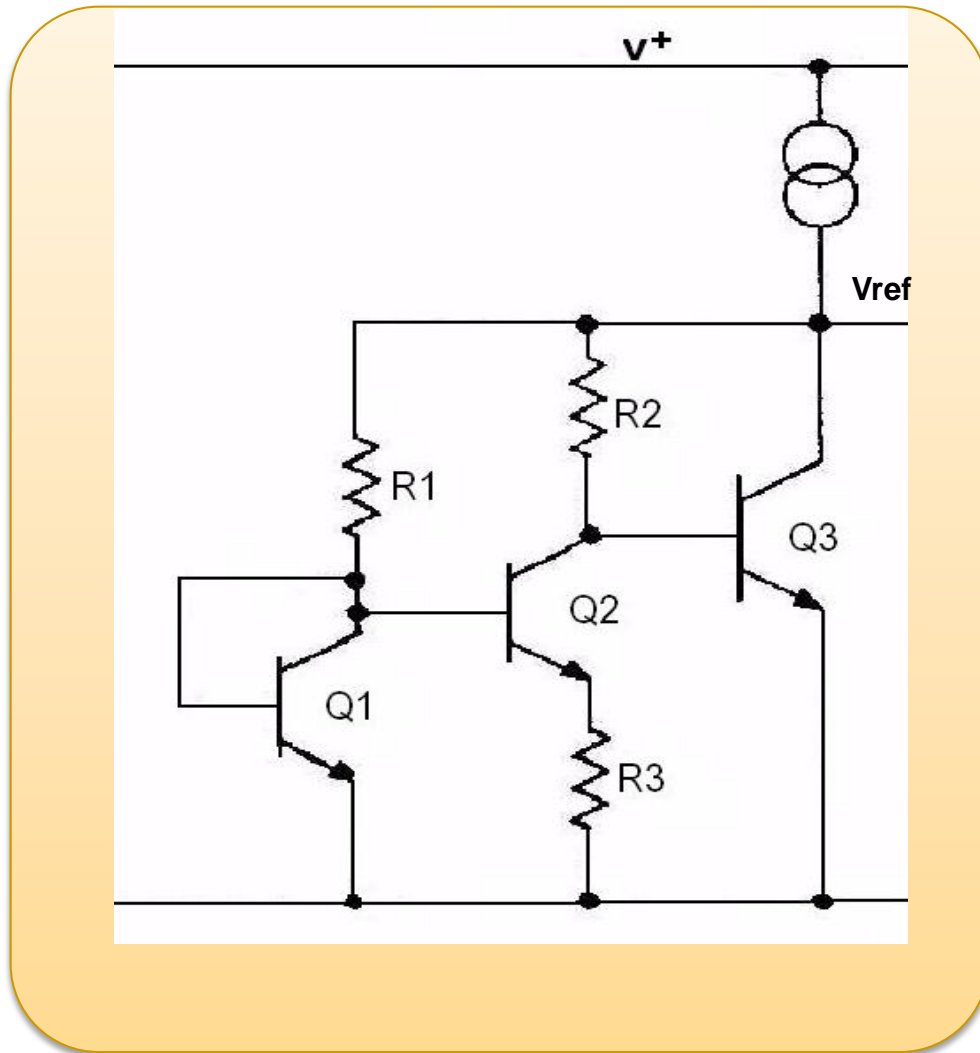
Actual Implementation of CMOS Band Gap Reference

Comparison of the Three Reference Approaches

- Breakdown voltage of a zener diode is typically larger than the power supplies used in modern circuits
- In most CMOS circuits depletion transistors are not typically available
- Available in both bipolar and CMOS technologies

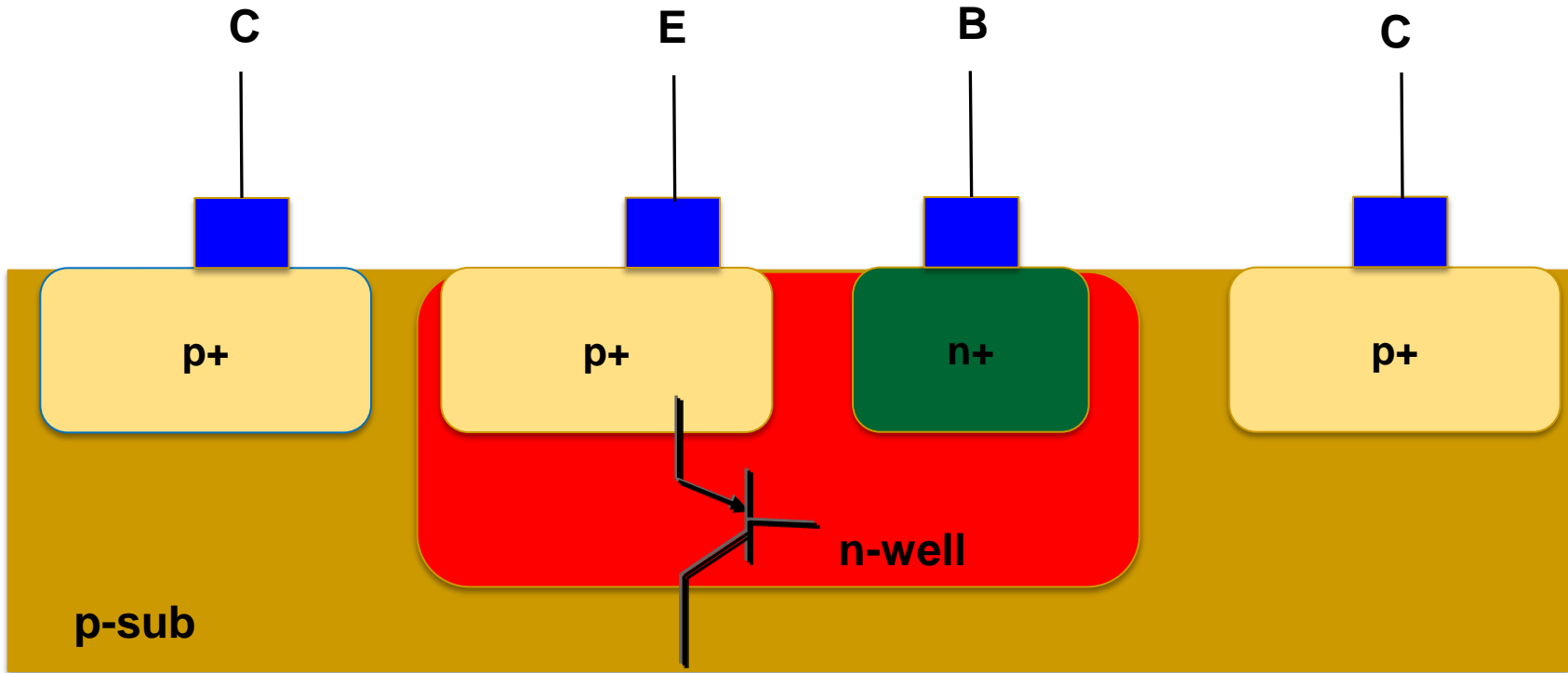


Implementation Using Bipolar Devices



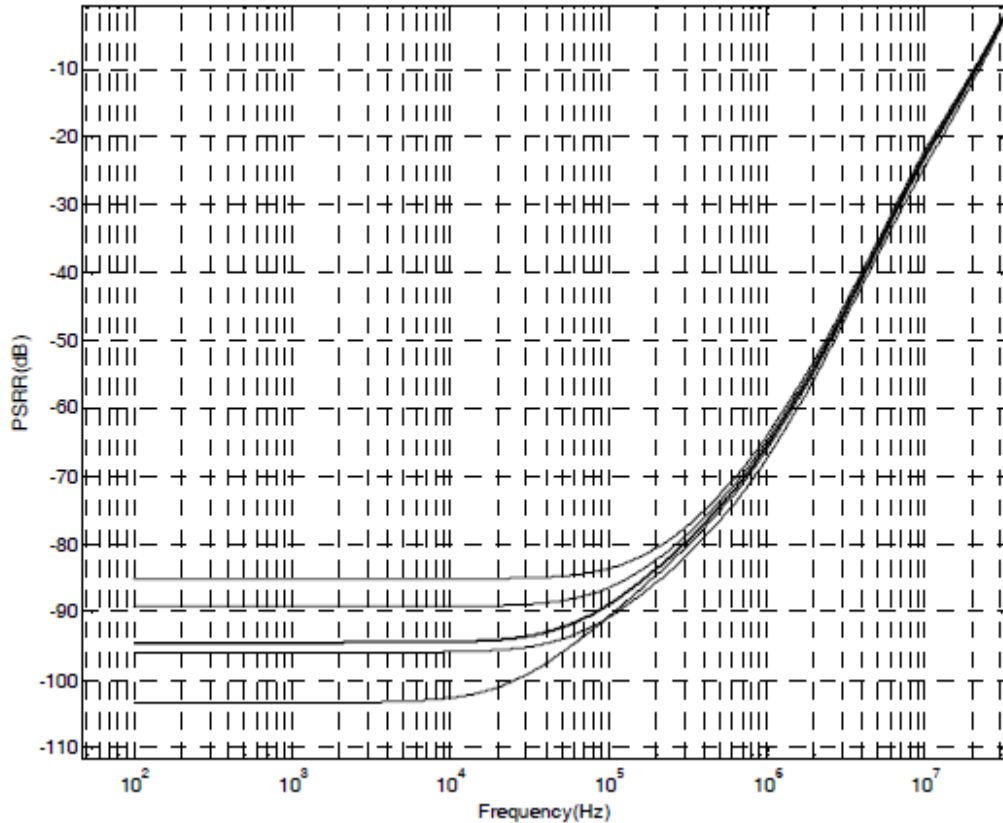
- Transistors **Q1** and **Q2** produce PTAT voltages across the resistors **R3** and **R2**.
- **Q3** drives the output to a voltage which is the sum of its **VBE** and the voltage across **R2**.
- When the output voltage is set to approximately the **bandgap voltage of silicon**, the voltage across **R2** will compensate the temperature coefficient of **VBE**, and the output voltage will have a **low TC**.

Compatibility with CMOS Technology



"parasitic" substrate PNP transistor
available in any CMOS technology

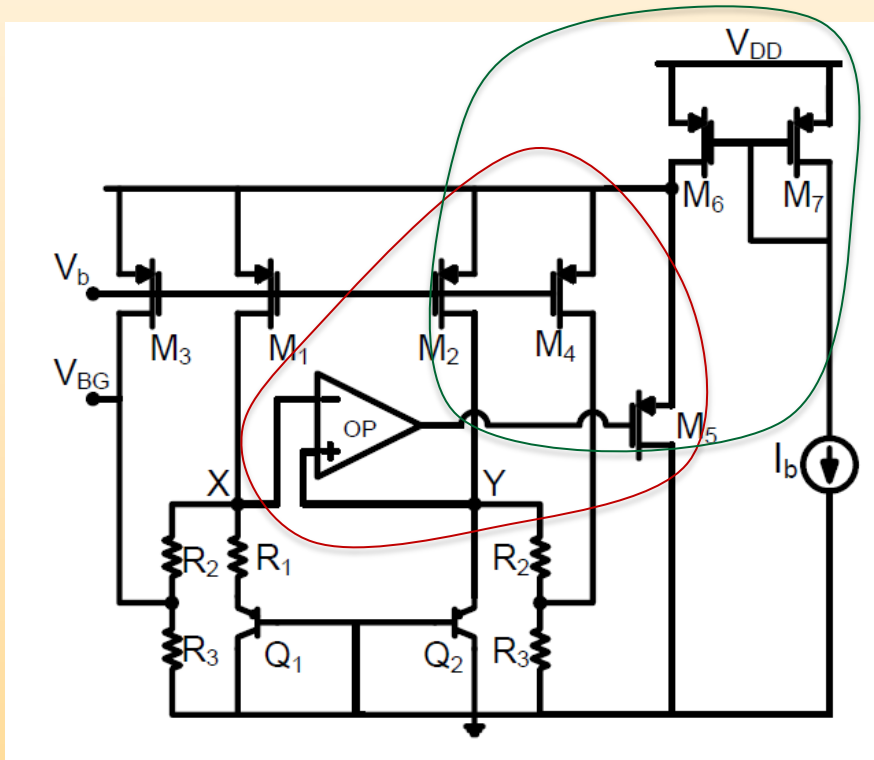
PSRR



Power Supply Rejection Ratio (PSRR)

Bandgap core is supplied from a current source instead of voltage supply to have less dependency on power supply

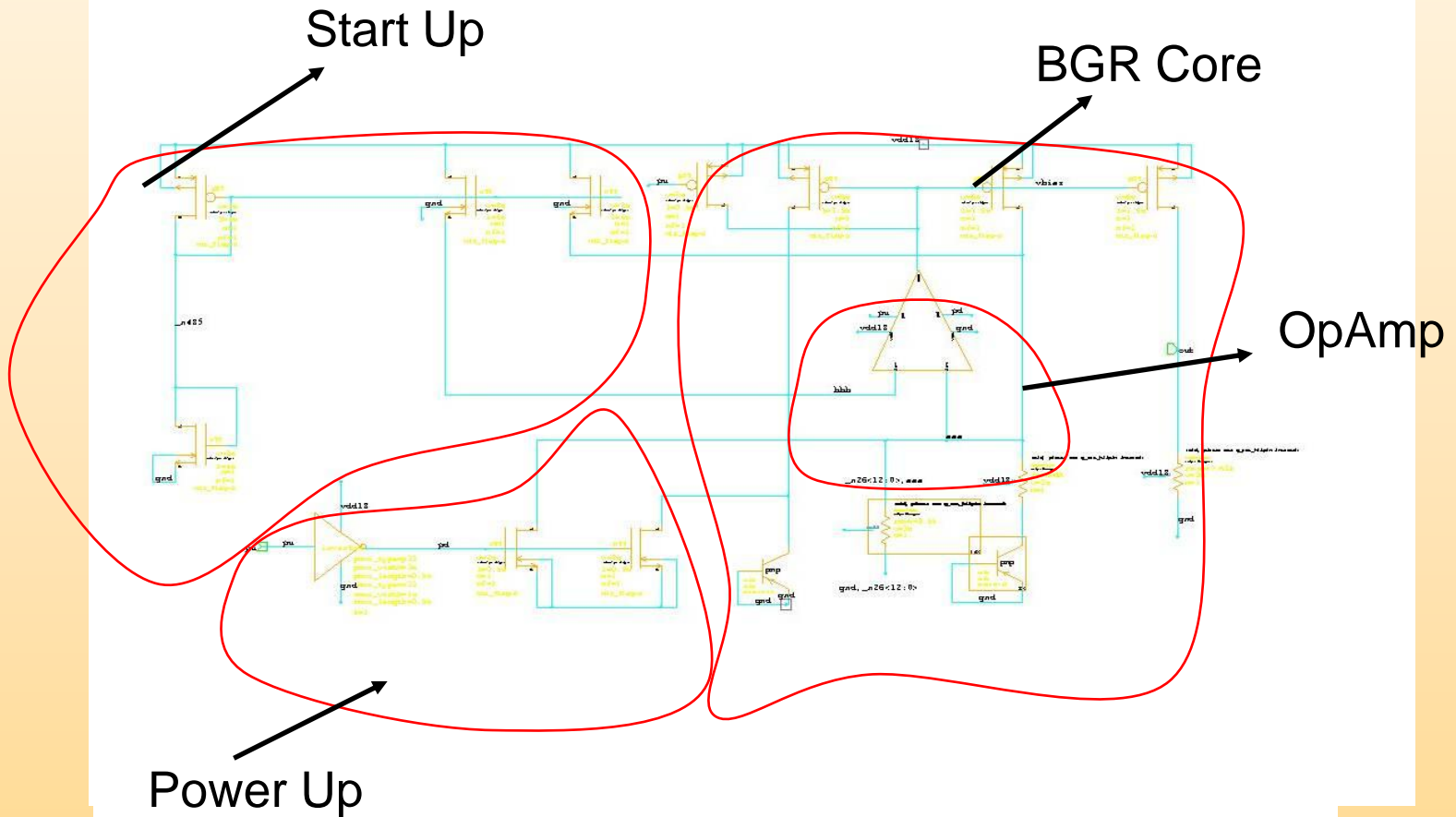
High PSRR Mechanism



High PSRR is obtained by applying these strategies

- The bandgap core must be supplied from regulated voltage made with a feedback loop
- The current reference that supplies the bandgap core designed wideband to have high PSRR, because the PSRR of this block is proportional to gain and bandwidth of Operational Amplifier

Implemented Circuit

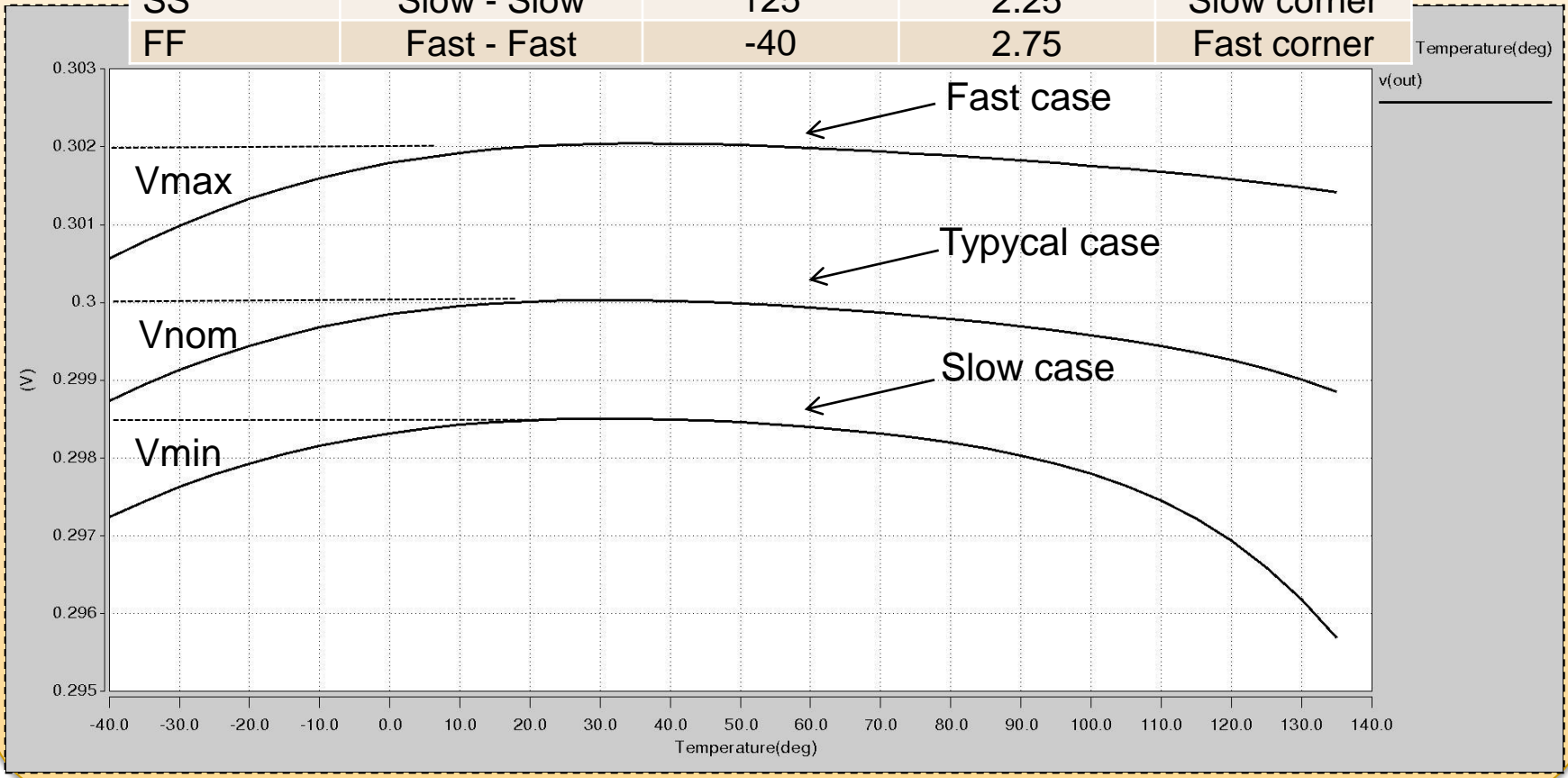


Why
Bell ?



Temperature Dependence

Corner Name	Process (NMOS proc. – PMOS proc.)	Temperature (T)	Power Supply (V)	Notes
TT	Typical - Typical	25	2.5	Typical corner
SS	Slow - Slow	125	2.25	Slow corner
FF	Fast - Fast	-40	2.75	Fast corner



Simulation Results

28nm technology

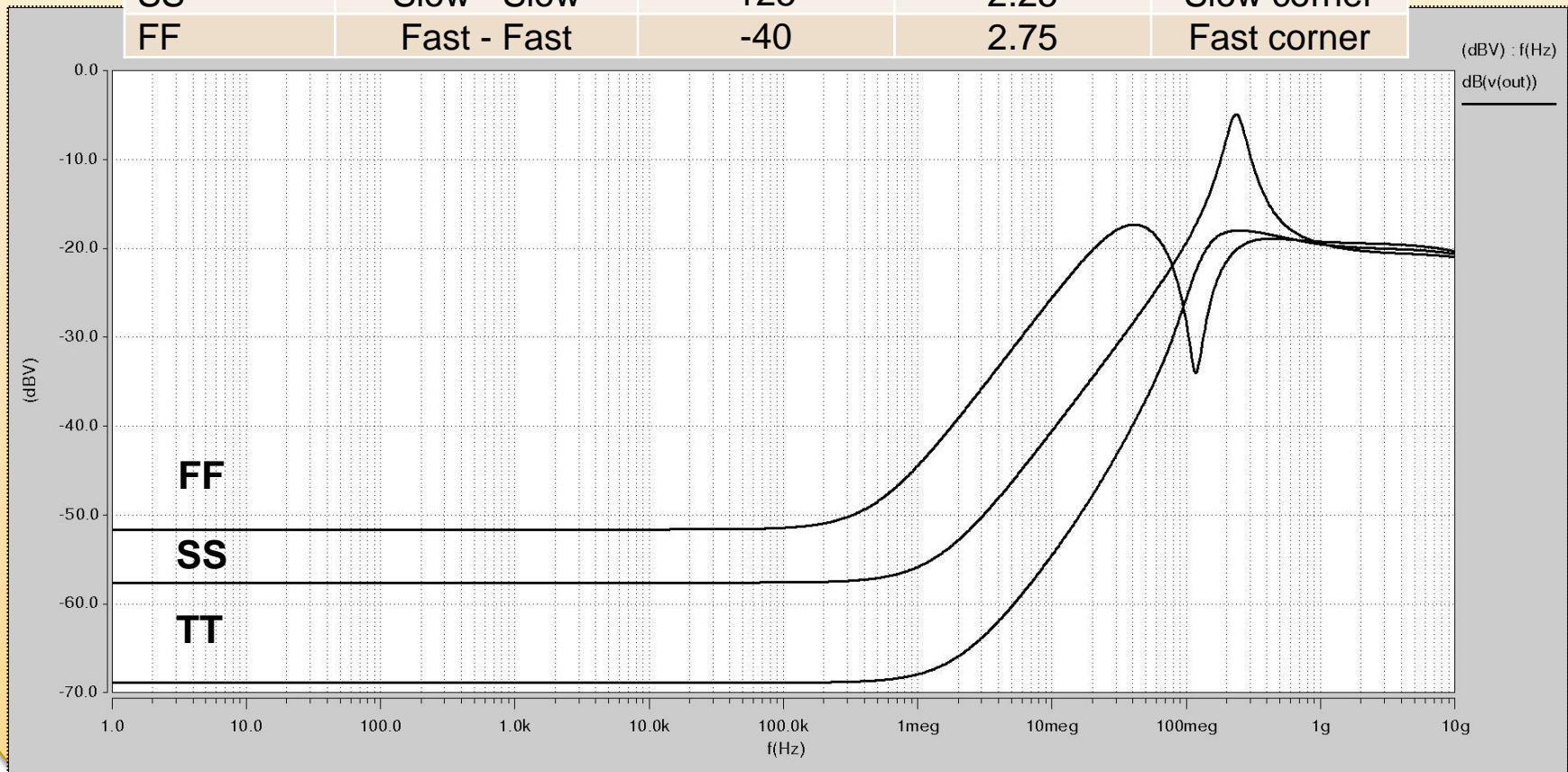
TT	Typical case	1.8V	25 ° C
SS	Worst case	1.62V	125 ° C
FF	Best case	1.98V	-40 ° C

Deviation (from above) = $V_{max} - V_{nom}/V_{typ} = 0.302 - 0.3 / 0.3 = 0.6\%$

Deviation (from below) = $V_{typ} - V_{min}/V_{typ} = 0.3 - 0.296 / 0.3 = -1.33\%$

PSRR for implemented circuit (1)

Corner Name	Process (NMOS proc. – PMOS proc.)	Temperature (T)	Power Supply (V)	Notes
TT	Typical - Typical	25	2.5	Typical corner
SS	Slow - Slow	125	2.25	Slow corner
FF	Fast - Fast	-40	2.75	Fast corner



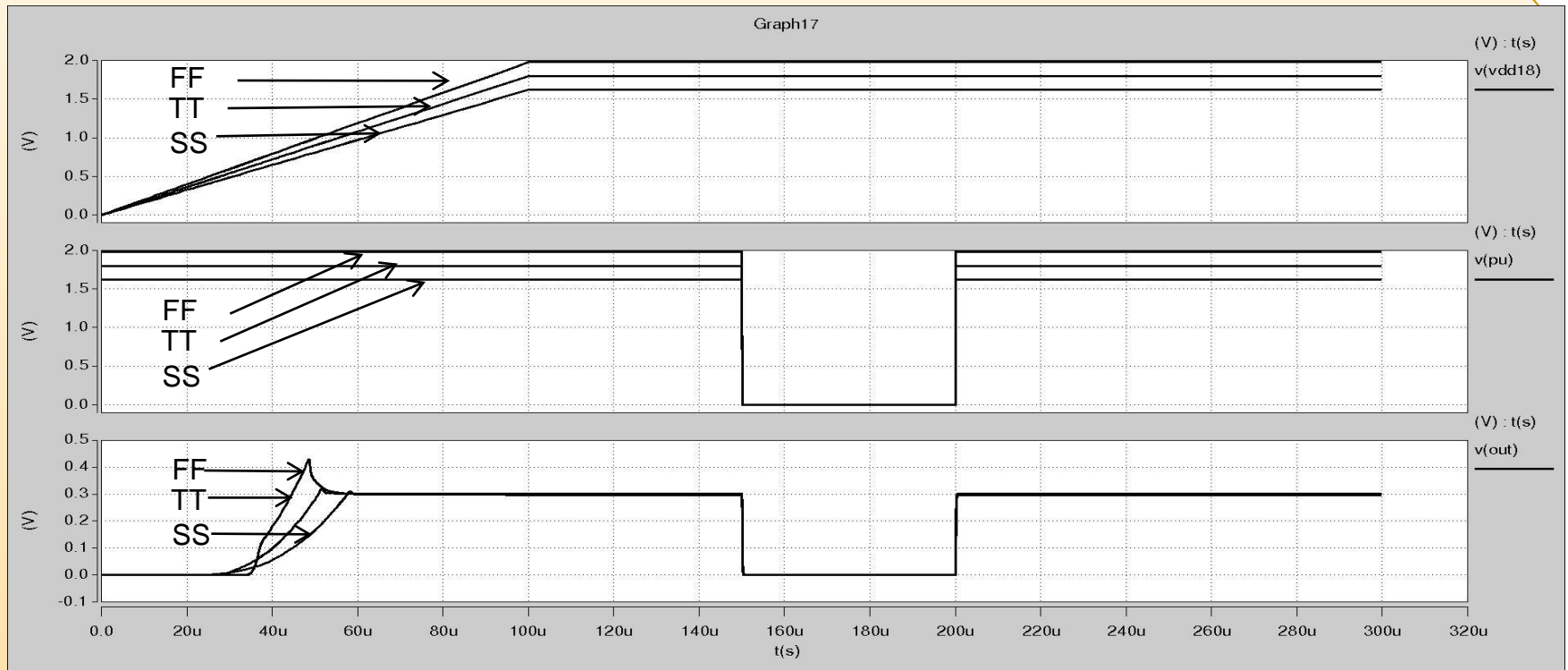
PSRR for implemented circuit (2)

$$\text{PSRR} = 20 \lg n$$

	1MHz	10MHz
TT	-68.9	-25.5
SS	-51.6	-40.5
FF	-54.2	-54.5



Power Up and Power Down



Corner Name	Process (NMOS proc. – PMOS proc.)	Temperature (T)	Power Supply (V)	Notes
TT	Typical - Typical	25	1.8	Typical corner
SS	Slow - Slow	125	1.62	Slow corner
FF	Fast - Fast	-40	1.98	Fast corner

Conclusion

Implemented 28nm 0.3V CMOS bandgap reference

The Performance of the Bandgap Circuit

Parameter	Measured
Supply Voltage Range Vref Vref Variation	1.8 V +/- 10% 0.3 V +/- 1.45
Temperature Range Vref Vref Variation	-40° C - 125° C 0.3 V +/- 1.33
PSRR Power Supply Rejection	1-1GHz Up to 70db 1Meg Up to 30db 10Meg

Thank you

